

NEW AND/OR INTERESTING IN MICROSCOPY

A REMINDER:

- * Aug. 16/17 - Microscopy Society of America (MSA) Conference.
- * Aug. 6/11 - Microbeam Analysis Society (MAS) Annual Meeting.

•* Leica AG in Heerbrugg (Switzerland) and Carl Zeiss in Oberkochen (Germany) have signed a letter of intent to form a joint subsidiary company to manufacture electron microscopes (EM). Both Leica and Zeiss intend to own 50% of this joint venture.

Both companies will combine their EM technologies and instruments, along with their appropriate production, distribution and customer service facilities, in the new company. By combining their EM forces, both companies feel that they will be able to offer a complete range of instruments to satisfy more effectively customers' application requirements for scanning and transmission electron microscopy. Traditional customer contacts for advice, applications assistance and service will not be changed.

The new venture will initially employ some 350 people. The Leica Corporation has 7500 employees world wide and the Carl Zeiss foundation employs 15,000 people throughout the world.

•* Leica SEM users worldwide are invited to enter the 1995 Leica SEM micrograph competition. The micrographs can be accepted as either traditional photographic prints or TIFF images. Prizes will be awarded taking into account originality, quality, content and preparation.

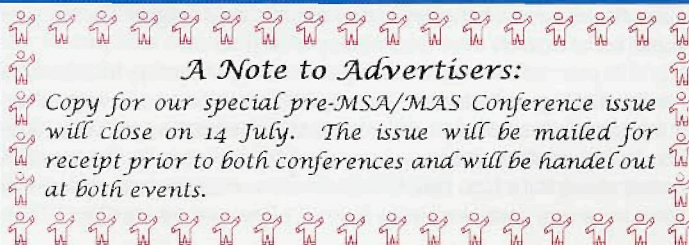
All entries must be received by August 31, 1995. The winner will be announced at Leica's fourth joint International Image Analysis and Scanning Electron Microscope User Conference, October 2 - 5, 1995.

If you would like to enter, please contact Toni Williamson at Leica Cambridge, phone number 011 44 1223 411411.

•* The XIV Pfefferkorn Conference on The Science of Biological Specimen Preparation for Microscopy will be held at The Shrine of Our Lady of the Snows, Belleville, IL (near St. Louis) on August 6 - 11, 1995.

The Conference aims at creating a platform for discussion of the preparation of cells and biomolecules for imaging *in vivo* and *in vitro*. This will provide a background for the correct interpretation of microscopic images. Specimen preparation techniques (for the following microscopy methods: fluorescence; differential-interference; real-time confocal laser scanning; infrared; atomic force and scanning tunneling; conventional, high resolution and field emission scanning electron; conventional, as well as high and intermediate voltage, transmission electron; etc.) to be discussed include whole mounts, immunolabelling, *in situ* hybridization, cryo-immobilization, freeze-fracture, freeze-drying, freeze-substitution, low temperature embedding, extractable embedments, thin film deposition, positive and negative staining, conductive staining, cryo-ultramicrotomy, etc.

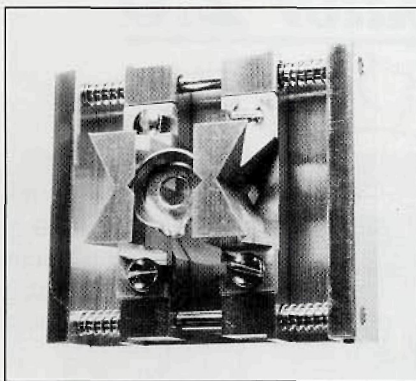
The U.S. Conference organizer is Dr. Marek Malecki, Integrated Microscopy Resource, University of Wisconsin, 1675 Observatory Drive, Madison, WI 53706; Phone (608)263-8481, FAX (608)233-2400, eMail MALECKI@MACC.WISC.EDU



A Note to Advertisers:

Copy for our special pre-MSA/MAS Conference issue will close on 14 July. The issue will be mailed for receipt prior to both conferences and will be handdel out at both events.

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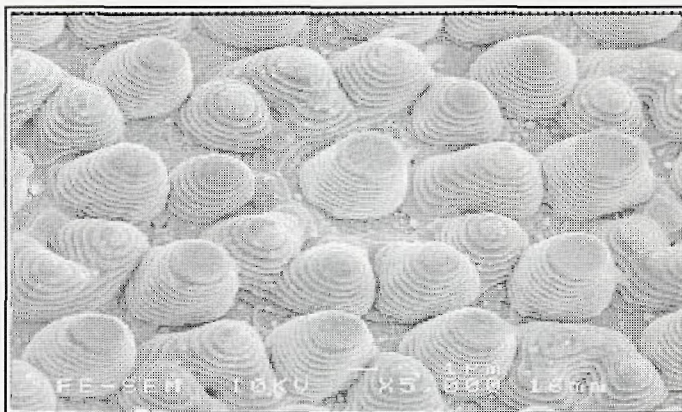
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